



RETURN BIDS TO:

RETOURNER LES SOUMISSIONS À:

Bid Receiving - PWGSC / Réception des soumissions -
TPSGC
11 Laurier St./ 11 rue, Laurier
Place du Portage, Phase III
Core 0B2 / Noyau 0B2
Gatineau, Québec K1A 0S5
Bid Fax: (819) 997-9776

**SOLICITATION AMENDMENT
MODIFICATION DE L'INVITATION**

The referenced document is hereby revised; unless otherwise indicated, all other terms and conditions of the Solicitation remain the same.

Ce document est par la présente révisé; sauf indication contraire, les modalités de l'invitation demeurent les mêmes.

Comments - Commentaires

Vendor/Firm Name and Address
Raison sociale et adresse du
fournisseur/de l'entrepreneur

Issuing Office - Bureau de distribution
Scientific, Medical and Photographic Division /
Division de l'équipement scientifique, des produits
photographiques et pharmaceutiques
L'Esplanade Laurier
140 O'Connor Street,
East Tower, 7th Floor
Ottawa
Ontario
K1A 0S5

Title - Sujet Environmental Scanning Electron	
Solicitation No. - N° de l'invitation 01E86-200373/A	Amendment No. - N° modif. 001
Client Reference No. - N° de référence du client 01E86-200373	Date 2019-11-27
GETS Reference No. - N° de référence de SEAG PW-\$\$PV-956-77894	
File No. - N° de dossier pv956.01E86-200373	CCC No./N° CCC - FMS No./N° VME
Solicitation Closes - L'invitation prend fin at - à 02:00 PM on - le 2019-12-03	
Time Zone Fuseau horaire Eastern Standard Time EST	
F.O.B. - F.A.B.	
Plant-Usine: <input type="checkbox"/> Destination: <input checked="" type="checkbox"/> Other-Autre: <input type="checkbox"/>	
Address Enquiries to: - Adresser toutes questions à: Courteau, Robert	Buyer Id - Id de l'acheteur pv956
Telephone No. - N° de téléphone (343) 550-1614 ()	FAX No. - N° de FAX () -
Destination - of Goods, Services, and Construction: Destination - des biens, services et construction:	

Instructions: See Herein

Instructions: Voir aux présentes

Delivery Required - Livraison exigée	Delivery Offered - Livraison proposée
Vendor/Firm Name and Address Raison sociale et adresse du fournisseur/de l'entrepreneur	
Telephone No. - N° de téléphone Facsimile No. - N° de télécopieur	
Name and title of person authorized to sign on behalf of Vendor/Firm (type or print) Nom et titre de la personne autorisée à signer au nom du fournisseur/ de l'entrepreneur (taper ou écrire en caractères d'imprimerie)	
Signature	Date

Amendment 001 is raised to publish answers to questions, and modify the Requirement:

Question 1

Is it possible to reduce the maximum photo magnification of 2,000,000X ?

Response:

No. This is the required maximum photo magnification for our purposes.

Question 2

Is 2.0 nm or less in Low Vacuum @ 1kV absolutely required?

Annex A: 2.1.2 Variable pressure or low vacuum mode resolution: Must be able to achieve 2.0 nm or less at 15 kV and 2.0 nm or less at 1 kV.

Response:

We will move this component to the point rated as it is highly desirable. See Modifications, below, to:

- RFP Section 4.2.1 (c);
- Annex A, Part 1, Section 2.1.2;
- Annex A, Part 1, Section 2.4;
- Annex A, Part 1, 2.4.1(b);
- Annex A, Part 2.1, Section 2.1.2;
- Annex A, Part 2.1, 2.4.1(b);

Question 3

Can we provide equipment which is not a multiple in-column detector configuration?

Response:

Yes, we will also accept a multiple in-lens detector configuration. See Annex A, Section & Criteria 2.1.8 modifications, below.

Question 4

Can we reduce the X, Y travel of a minimum of 120 x 100 mm, respectively?

Response:

No, this is a requirement. A large stage travel is required to accommodate after-market motorized specimen holders.

Question 5

Our microscope includes an upgraded system and software from within the last year, can we submit it for evaluation?

Response:

The reason for these criteria [Annex A: 1.4 & 2.1.23] is to avoid new untested models that had no record in the field. New models often have a record of being problematic in the first year. New and upgraded software often contains "bugs" that need to be addressed, whereas proven software has already worked out these issues. As for the requirement for Windows 10, all of AAFC has been converted to Windows 10 such that any instrument operated by a system less than that is not supported by the AAFC LAN. Since the instrument will have multiple users there needs to be a way of transferring data and images efficiently.

Question 6

As the typical timeframe for the delivery of such a microscope ranges from 4-6 months, is the client able to accept delivery after March 31st, 2020?

Response:

All proposals must adhere to this delivery schedule, no extensions will be permitted to the delivery of the goods or services of the requirement.

Question 7:

Do you require an Annual Service Maintenance Contract for this complete system?

Response:

No.

1.) We require a minimum 1 year warranty on the FE Emitter (electron gun) (Annex A: 2.1.31). Longer warranties are highly desirable (Annex A: 2.4.16).

2.1.31 The Schottky FE Emitter (electron gun) must be covered by a warranty included with the purchase at no cost, not an 'extended' warranty, for all parts and labor for a minimum of 1 year.

2.4.16 For the Schottky FE Emitter (electron gun), the bidder includes a warranty period of 1 year (mandatory minimum), 3 years (10 points), or 5 years (20 points).

2.) We require that the vendor guarantees to not declare the system obsolete and discontinue technical and material support during the first 10 years following purchase (Annex A: 2.1.32). Continued support for the lifetime of the system is highly desirable (Annex A: 2.4.18).

2.1.32 The vendor shall demonstrate the availability of after-sales on-site service, including service of the EDS detector for at least 10 years after the purchase. A signed certification by bidder that they will provide on-site service 10 years following Contract Award.

2.4.18 A signed certification by bidder that they will provide on-site service 10 years following Contract Award (mandatory). A signed certification by bidder that they will provide on-site service for the lifetime of the system (10 points).

MODIFICATIONS AND ADDITIONS

Modify RFP Section 4.2.1 (c)

Delete: "obtain the required minimum of 100 points overall for the technical evaluation criteria which are subject to point rating. The rating is performed on a scale of 205 points."

Insert: "obtain the required minimum of 110 points overall for the technical evaluation criteria which are subject to point rating. The rating is performed on a scale of 215 points."

Modify Annex A, Part 1, Section 2.1.2

Delete: Variable pressure or low vacuum mode resolution: Must be able to achieve 2.0 nm or less at 15 kV and 2.0 nm or less at 1 kV.

Insert: Variable pressure or low vacuum mode resolution: Must be able to achieve 2.0 nm or less at 15 kV.

Modify Annex A, Part 1, Section 2.4

Delete: "A minimum 100 points out of 205 total points is required."

Insert: "A minimum 110 points out of 215 total points is required."

Insert Annex A, Part 1, 2.4.1(b)

Insert: "2.4.1 b) Variable pressure or low vacuum mode resolution: Must be able to achieve 2.0 nm or less at 15 kV. (Mandatory). Variable pressure or low vacuum mode resolution: 2.0 nm or less at 1 kV. (10 Points)"

Modify Annex A, Part 2.1, Section 2.1.2

Delete: "Variable pressure or low vacuum mode resolution: Must be able to achieve 2.0 nm or less at 15 kV and 2.0 nm or less at 1 kV."

Insert: "Variable pressure or low vacuum mode resolution: Must be able to achieve 2.0 nm or less at 15 kV."

Insert Annex A, Part 2.1, 2.4.1(b)

Insert:

2.4.1 b	Variable pressure or low vacuum mode resolution: 2.0 nm or less at 1 kV.	10 points
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Modify Annex A, Part 1, Section 2.1.8:

Delete: 2.1.8 Detectors : A multiple "in-column" detector configuration is required. This configuration must allow collection of all types of signal responses from surface micro-structural information to compositional information, to topographical information as well as crystallographical information.

Insert: 2.1.8 Detectors : A multiple in-column and/or in-lens detector configuration is required. This configuration must allow collection of all types of signal responses from surface micro-structural information to compositional information, to topographical information as well as crystallographical information.

Modify Annex A, Part 2.1, Criteria 2.1.8:

Delete:

2.1.8	Detectors : A multiple "in-column" detector configuration is required. This configuration must allow collection of all types of signal responses from surface micro-structural information to compositional information, to topographical information as well as crystallographical information.	Mandatory
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Insert:

2.1.8	Detectors : A multiple in-column and/or in-lens detector configuration is required. This configuration must allow collection of all types of signal responses from surface micro-structural information to compositional information, to topographical information as well as crystallographical information.	Mandatory
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